

Notice of References Cited	Application/Control No. 10/065,742		Applicant(s)/Patent Under Reexamination GONG ET AL.	
	Examiner Toan M Le		Art Unit 2863	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,918,627	04-1990	Garcia et al.	702/82
	C	US-5,586,052	12-1996	Iannuzzi et al.	703/1
	D	US-6,612,044	09-2003	Raab et al.	33/503
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	F	US-5,949,693	09-1999	Tandler, William	703/1
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	H	US-5,323,333	06-1994	Johnson, Richard W.	703/1
	I	US-2004/0030427	02-2004	Drake et al.	700/97
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ngoi et al., Graphical Approach to Assembly Tolerance Stack Analysis- the "Quickie" GDT Method, 1997, Proc. Instn. Mech. Engrs., Vol. 211, Part B, Pages 463-472.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.